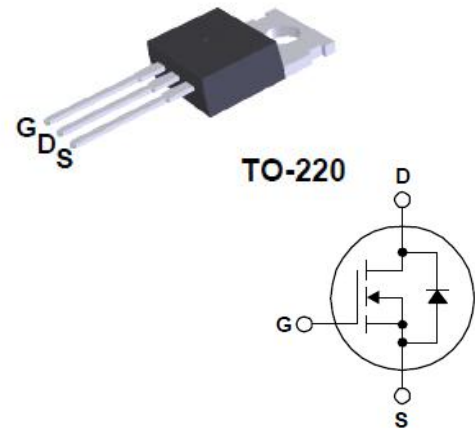


130V N-Channel Trench Power MOSFET

Features

- 130V/104A
 $R_{DS(ON)}=8.5m\Omega(Typ.)@V_{GS}=10V$
- Ultra Low On-Resistance
- High UIS and UIS 100% Test
- Special Designed for E-Bike Controller Application

PIN DESCRIPTION



Applications

- 96V E-Bike controller applications
- Hard Switched and High Frequency Circuits
- Uninterruptible Power Supply

Part Number	Package	Marking	ROHS Status	Packing
SI130N01B	TO-220	SI130N01B	Pb-Free	Box (Tube)

Absolute Maximum Ratings ($T_A=25^{\circ}C$ unless otherwise noted)

Symbol	Parameter	Typical	Unit	
V_{DSS}	Drain-Source Voltage ($V_{GS}=0V$)	130	V	
V_{GSS}	Gate-Source Voltage ($V_{DS}=0V$)	± 25	V	
I_D	Continuous Drain Current	$T_C=25^{\circ}C$	104	A
		$T_C=100^{\circ}C$	73	A
I_{DM}	Pulsed Drain Current Tested	416	A	
T_{STG}, T_J	Storage Temperature and Operating Junction Range	-55~150	$^{\circ}C$	
dv/dt	Peak Diode Recovery Voltage	7	V/ns	
E_{AS}	Single pulse Avalanche energy	1600	mJ	
P_D	Power dissipation	$T_C=25^{\circ}C$	348	W

1. Repetitive Rating: Pulse width limited by maximum junction temperature

2. E AS condition: $T_J=25^{\circ}C, V_{DD}=50V, V_G=10V, R_G=25\Omega$

Thermal Resistance

Parameter	Symbol	Value	Unit
Thermal resistance, junction - case. Max	R_{thJC}	0.43	$^{\circ}C/W$

Electrical Characteristics ($T_A=25^{\circ}\text{C}$ unless otherwise noted)

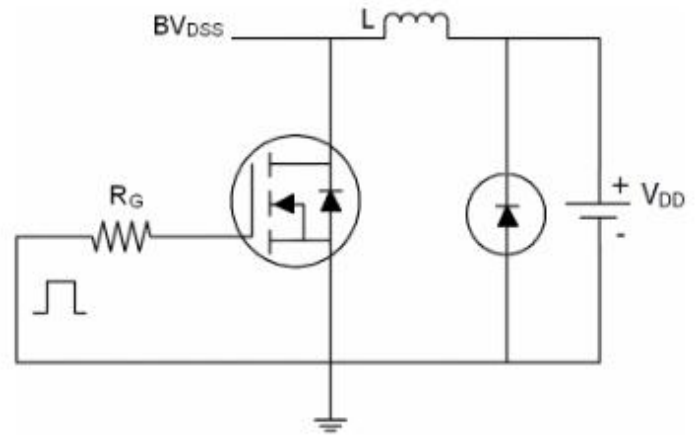
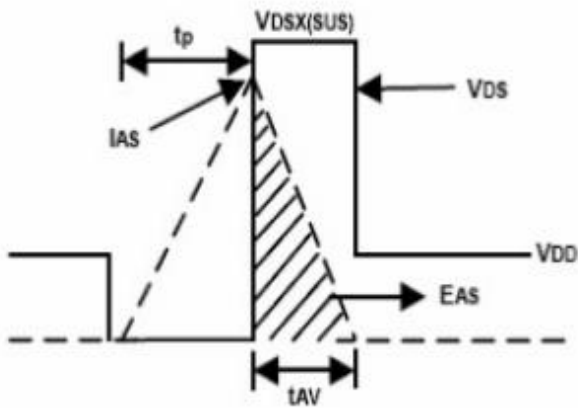
Symbol	Parameter	Test Conditions	Min	TYP	Max	Unit
Static Characteristics						
BV_{DSS}	Drain-source breakdown voltage	$V_{GS}=0V, I_D=250\mu A$	130	-	-	V
$V_{GS(th)}$	Gate threshold voltage	$V_{DS}=V_{GS}, I_D=250\mu A$	3	-	5	V
I_{DSS}	Zero gate voltage drain current	$V_{DS}=130V, V_{GS}=0V$	-	-	1	μA
		$T_C=125^{\circ}\text{C}$	-	-	10	
I_{GSS}	Gate-source leakage current	$V_{GS}=\pm 20V, V_{DS}=0V$	-	-	± 100	nA
$R_{DS(on)}$	Drain-source on-state resistance	$V_{GS}=10V, I_D=40A$	-	8.5	12	m Ω
Dynamic Characteristic						
G_{FS}	Forward Transconductance	$V_{DS}=10V, I_D=15A$	20	-	-	S
C_{iss}	Input Capacitance	$V_{GS}=0V, V_{DS}=25V, f=1\text{MHz}$	-	9152	-	pF
C_{oss}	Output Capacitance		-	799	-	pF
C_{rss}	Reverse Transfer Capacitance		-	406	-	pF
$t_{d(on)}$	Turn-on delay time	$I_D=40A, V_{GS}=10V, V_{DD}=65V, R_L=15\Omega, R_G=2.5\Omega$	-	40	-	nS
t_r	Rise time		-	72	-	
$t_{d(off)}$	Turn-off delay time		-	103	-	
t_f	Fall time		-	35	-	
Gate Charge Characteristics						
Q_G	Gate Total Charge	$V_{GS}=10V, V_{DS}=50V, I_D=40A$	-	274	-	nC
Q_{gs}	Gate-Source charge		-	56	-	
Q_{gd}	Gate-Drain charge		-	113	-	
Source-Drain Diode Characteristics						
I_{SD}	Source-Drain Current(Body Diode)	-	-	104	-	A
I_{SDM}	Pulsed Source-Drain Current(Body Diode)	-	-	416	-	A
V_{SD}	Body Diode Forward Voltage	$V_{GS}=0V, I_{SD}=40A, T_J=25^{\circ}\text{C}$	-	0.85	0.99	V
t_{rr}	Body Diode Reverse Recovery Time	$T_J=25^{\circ}\text{C}, I_F=40A, di/dt=100A/\mu s$	-	80	-	nS
Q_{rr}	Body Diode Reverse Recovery Charge		-	200	-	nC

Notes:

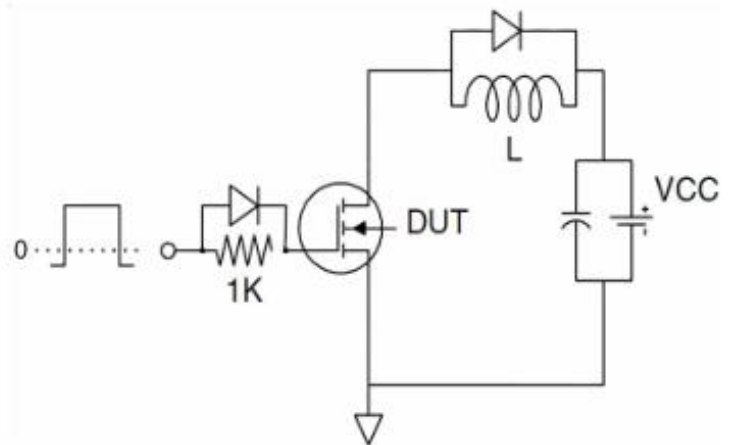
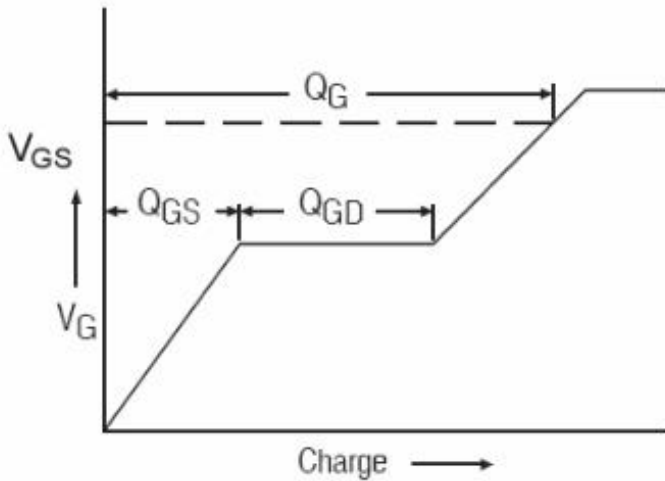
 1. Pulse Test: Pulse Width $\leq 300\mu s$, Duty Cycle $\leq 1.5\%$, $R_G=25\Omega$, Starting $T_J=25^{\circ}\text{C}$

Switching Time Test Circuit and Wave forms

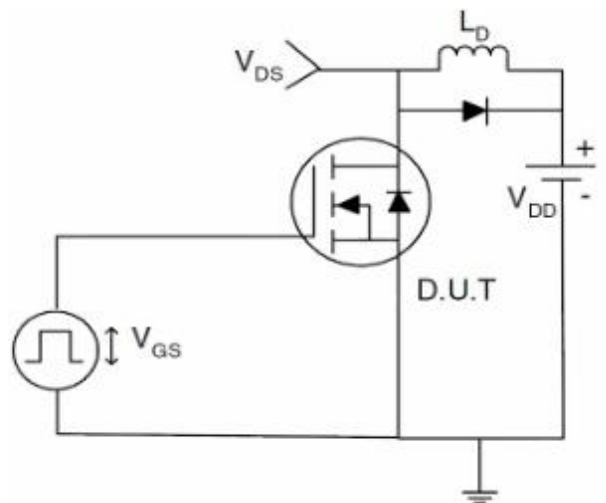
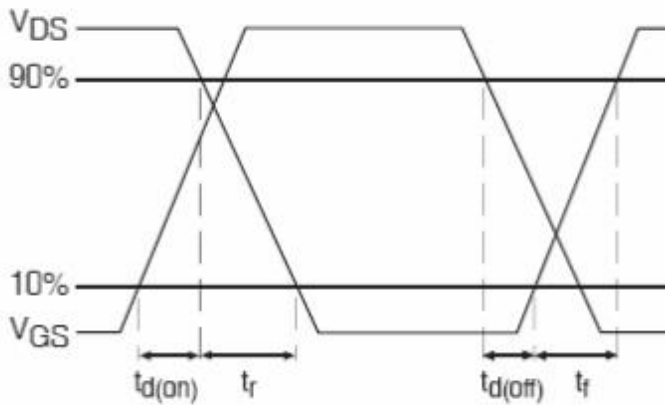
1) E_{AS} Test Circuits



2) Gate Charge Test Circuit:



3) Switch Time Test Circuit:



Typical Operating Characteristics

Figure1. Output Characteristics

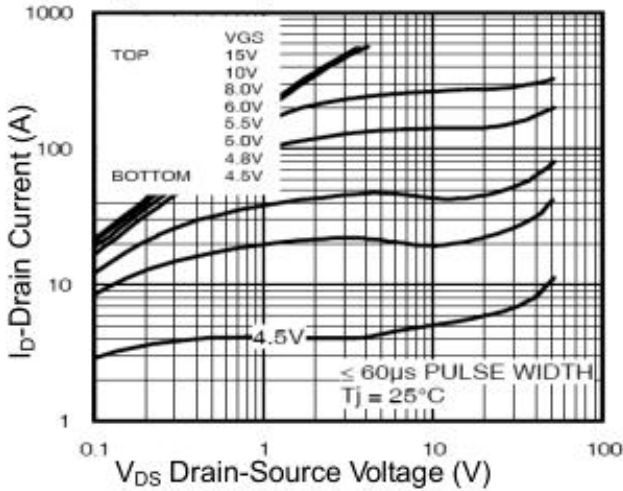


Figure2. Transfer Characteristics

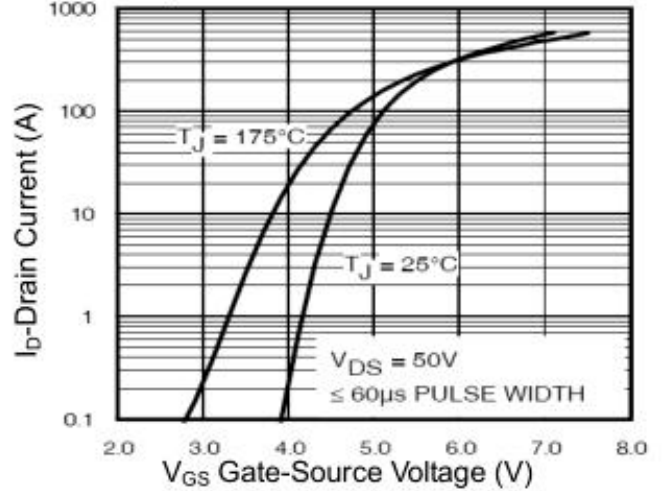


Figure3. BVDSS vs Junction Temperature

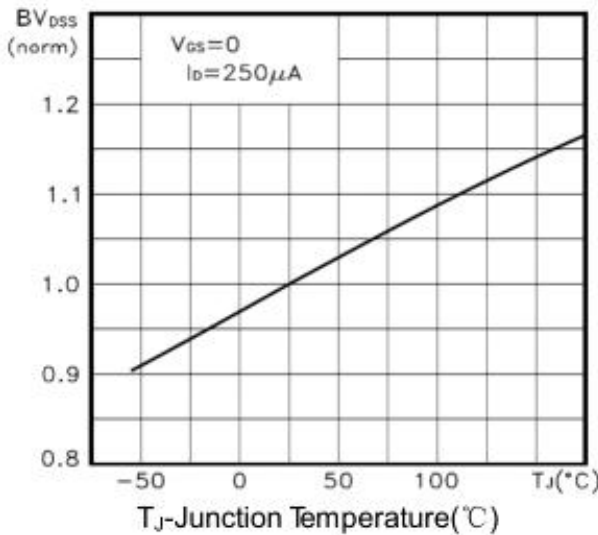


Figure4. ID vs Junction Temperature

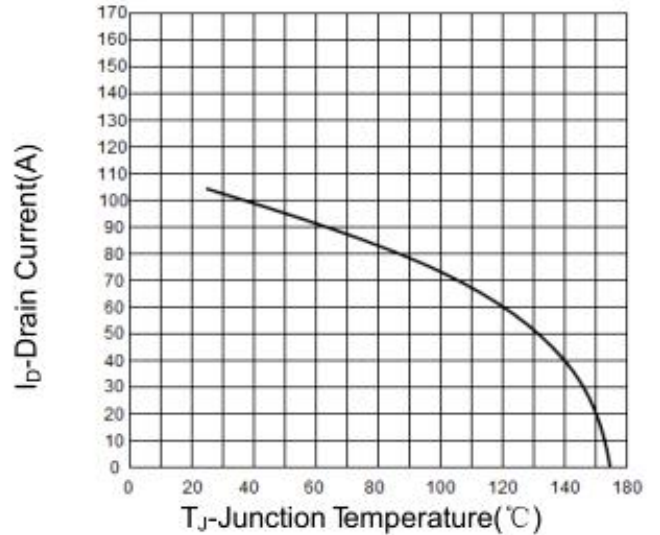


Figure5. VGS(th) vs Junction Temperature

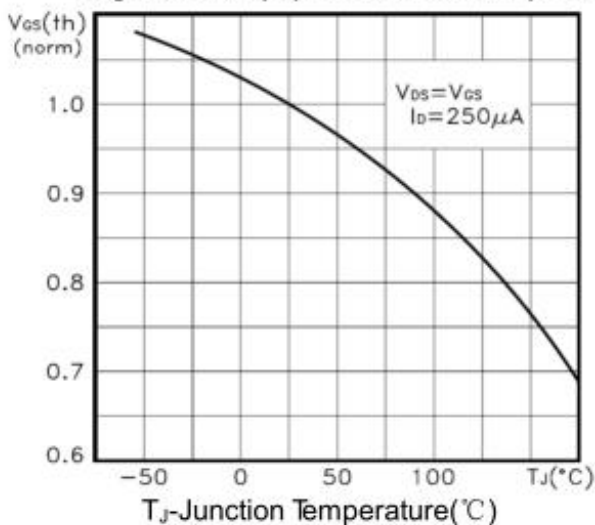
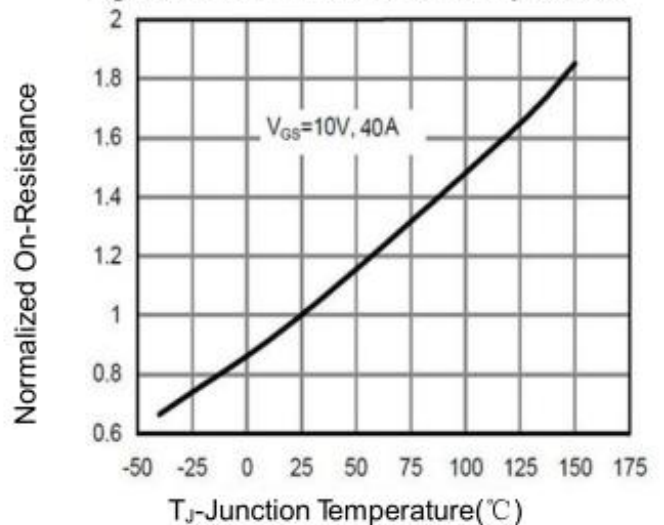
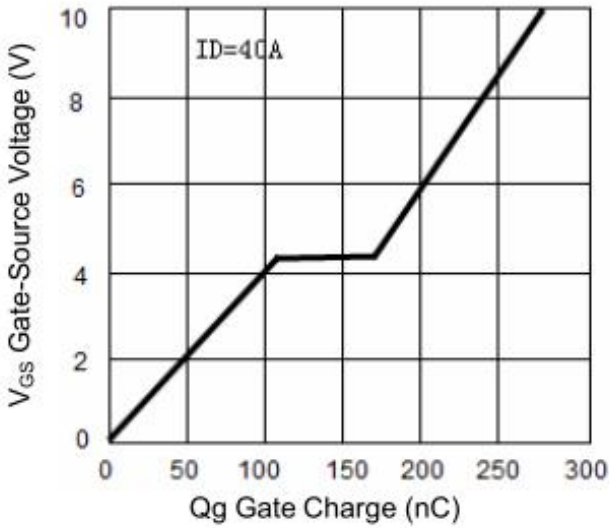
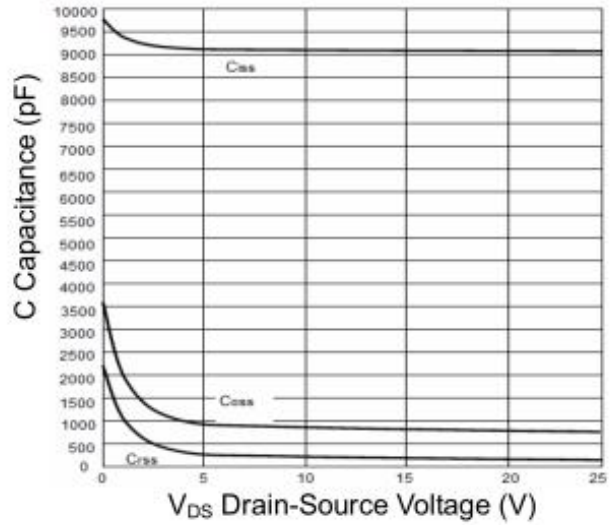
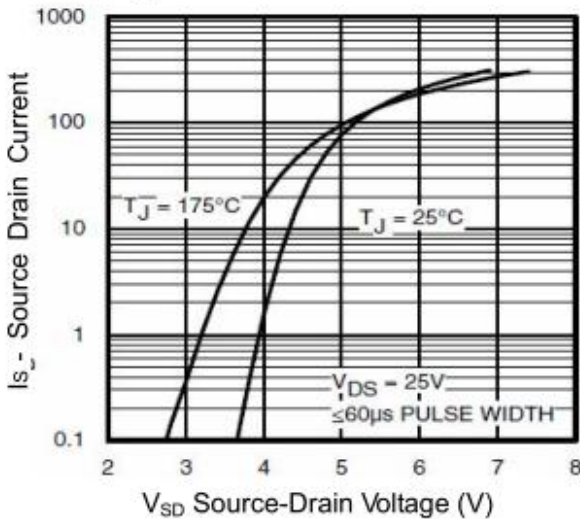
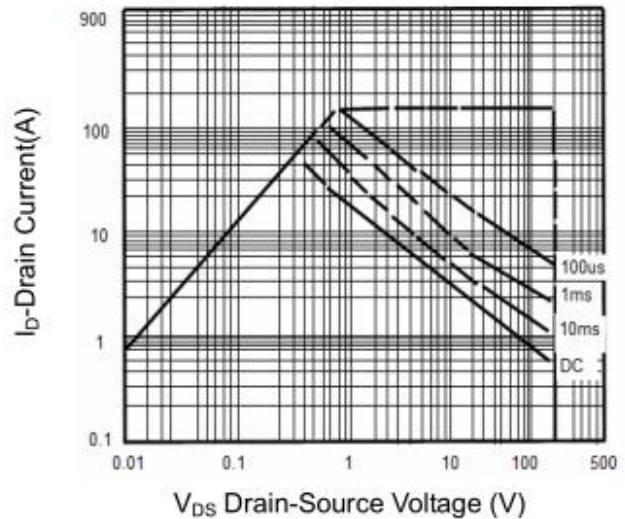
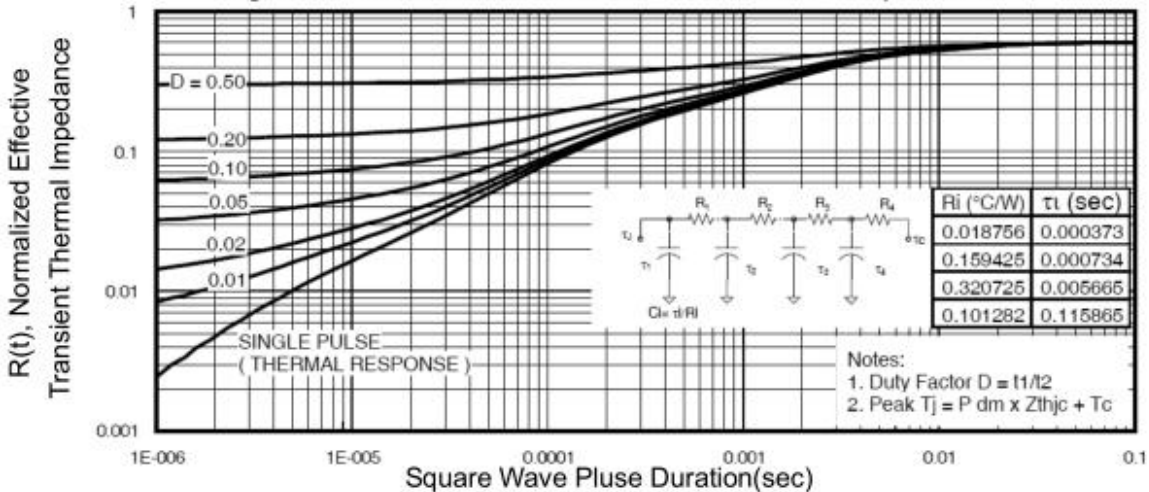


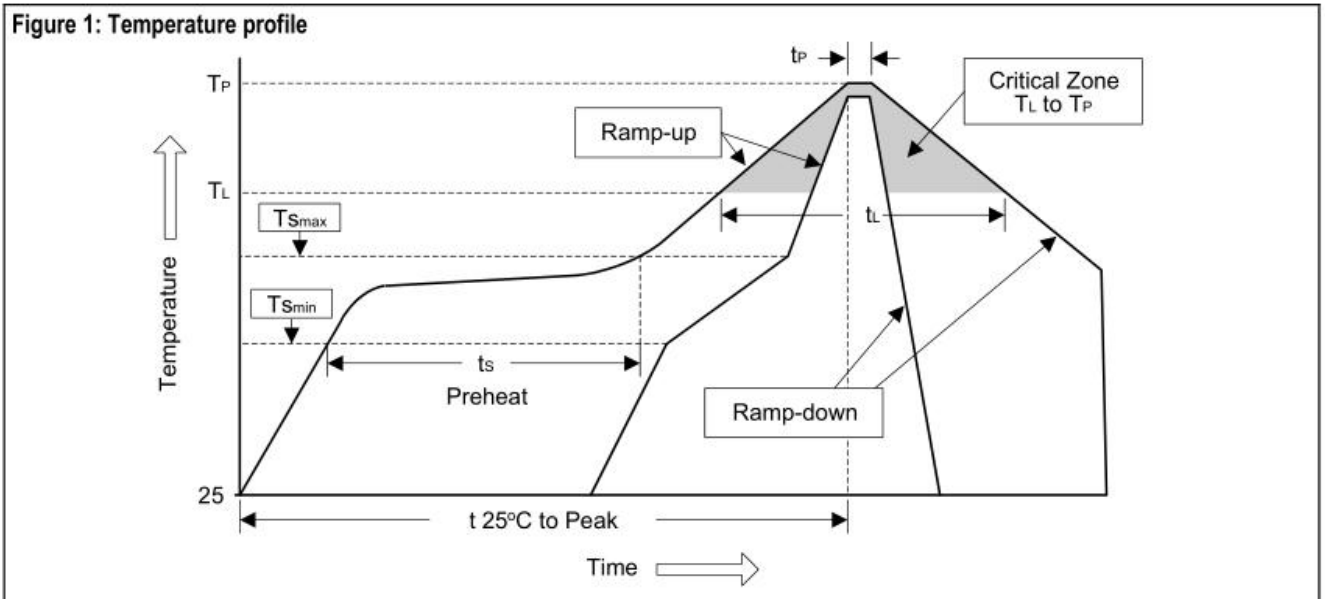
Figure6. Rds(on) Vs Junction Temperature



Typical Operating Characteristics (CONT.)
Figure7. Gate Charge

Figure8. Capacitance vs Vds

Figure9. Source- Drain Diode Forward

Figure10. Safe Operation Area

Figure11. Normalized Maximum Transient Thermal Impedance


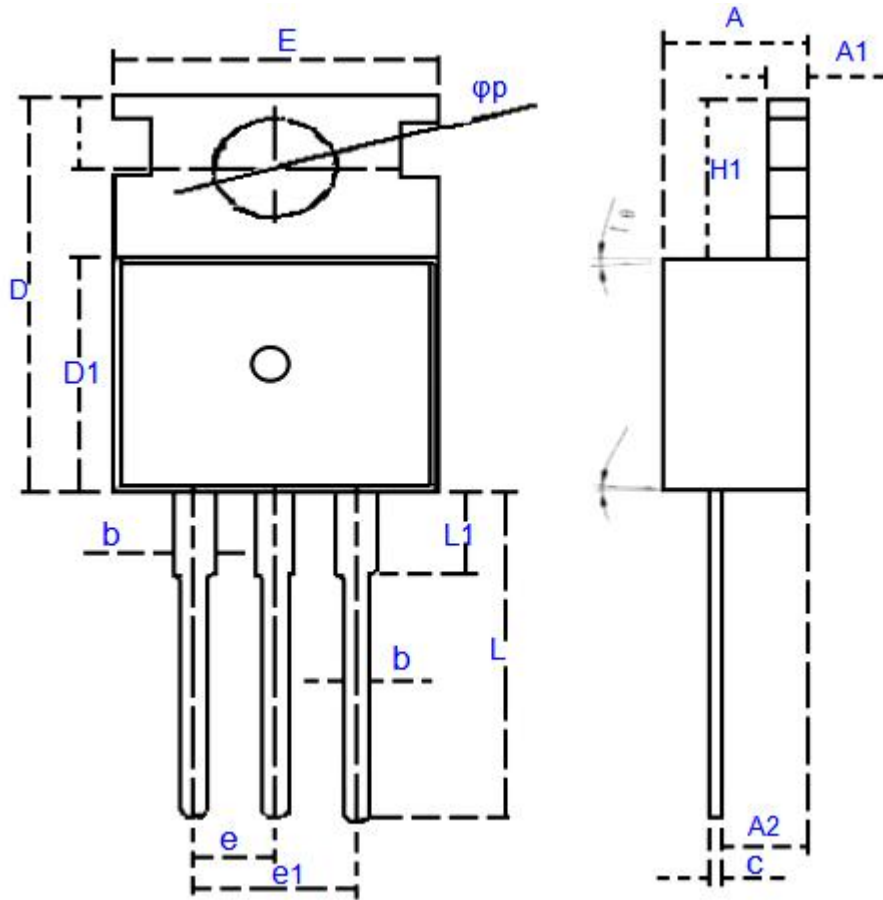
Soldering Methods for Products

Profile Feature	Sn-Pb Eutectic Assembly	Pb-Free Assembly
Average ramp-up rate(TL to TP)	<3°C/sec	<3°C/sec
Preheat		
-Temperature Min(Ts min)	100°C	150°C
-Temperature Max(Ts max)	150°C	200°C
-Time(min to max)(ts)	60 to 120 sec	60 to 180 sec
Ts max to TL		
- ramp-up rate	<3°C/sec	<3°C/sec
Time maintained above:		
-Temperature(TL)	183°C	217°C
-Time(TL)	60 to 150 sec	60 to 150 sec
Peak Temperature(TP)	240°C+0/-5°C	250°C+0/-5°C
Time within 5°C of actual Peak Temperature	10 to 30 sec	20 to 40 sec
Ramp-down Rate	<6°C/sec	<6°C/sec
Time 25 °C to Peak Temperature	<6 minutes	<8 minutes



- Note :**
- 1.Storage environment: Temperature=10°C to 35@Humidity=45%±15%
 - 2.Reflow soldering of surface-mount devices
 - 3.Flow(wave) soldering(solder dipping)

Products	Peak Temperature	Dipping Time
Pb devices	245°C±5°C	5sec±1sec
Pb-free devices	250°C+0/-5°C	5sec±1sec

Package Outline


Millimeters					
Symbol	Min	Max	Symbol	Min	Max
A	4.2	4.8	E	9.6	10.5
A1	1.28	1.34	e	2.54 Typ.	
A2	2.2	2.6	e1	5.08	5.18
b	0.69	0.91	H1	6.1	7.0
b1	1.17	1.37	L	12.9	13.5
c	0.42	0.51	L1	2.9	3.7
D	15.1	16.3	ΦP	3.4	3.8
D1	9.0	9.5	$\theta 1$ (°)	1	5

■ Important Notice

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Any semiconductor under specific conditions are possible to certain failure or malfunction rate ; Customers are responsible in the use of Si-Trend products to system design and manufacturing in compliance with safety standards and adopting safety measures 、 To avoid the potential risk of failure may cause the personal safety and property loss ◦

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20190820	A.1	/	8